

# S400UX

# Parametric Test System



- **Open, expandable test environment simplifies development of test programs without coding**
- **Well suited for both novice and expert system users**
- **Simplifies migration from VAX/VMS environment to the UNIX environment**
- **Incorporate third-party software into the test environment for expanded capabilities at minimal added cost**
- **Applications for every phase of device design, development, and production**

The S400UX is an integrated package of hardware and software tools, offering semiconductor fabs the industry's most complete solution for automated parametric testing.

### Wide Test Development Flexibility

There's no need to learn a high-level programming language—even novice users can create executable test sequences in minutes without ever writing a line of code. However, the software also includes tools that make it equally suitable for experienced test programmers, offering wide flexibility for those who prefer to write their own routines or modify those included in the package. The S400UX relies on the Keithley Test Environment (KTE) software interface for test development and execution.

### Easy Migration from S425/S450

The S400UX is hardware compatible with its predecessors, the S425 and S450 systems, and offers a cost-effective software migration path for facilities planning to upgrade to a UNIX test environment.

### Wide Range of Hardware Options

In addition to the standard source/measure instrumentation, the S400UX can be customized with a variety of options to tailor it for particular applications.

### Capacitance Meters

The S400UX can be equipped with high speed, single-frequency capacitance meters operating at either 100kHz or 1MHz. These units can also measure conductance to correct for series resistance in capacitance measurements. If multi-frequency capacitance measurements are required, an Agilent 4284 LCR meter can be integrated into the system.

### Microvoltmeter Option

If low voltage measurements are needed, a Keithley Model 2000 DMM can be added to provide microvolt-level measurement resolution.

### Frequency Measurements

The optional Keithley Model 776 Frequency Counter allows the S400UX to measure devices such as ring oscillators.

### High Voltage Option

For characterizing high voltage devices, the S400UX can be equipped with the Keithley Model 237 Source-Measure Unit and an external matrix to allow measurements up to 1100V.

### Pulse Generator Option

The S400UX supports the Agilent 81110 pulse generator for applications such as flash memory testing.

## Ordering Information

**S400UX UNIX-Based  
Parametric Test  
System**

**This product is available with  
an Extended Warranty.**

1.888.KEITHLEY (U.S. only)

[www.keithley.com](http://www.keithley.com)

**KEITHLEY**

A GREATER MEASURE OF CONFIDENCE

UNIX-based parametric test system

SEMICONDUCTOR